

MITSUBISHI HIGH SPEED CMOS M74HC174P/FP/DP

HEX D-TYPE FLIP-FLOP WITH COMMON CLOCK AND RESET

DESCRIPTION

The M74HC174 is a semiconductor integrated circuit consisting of six positive-edge triggered D-type flip flops with common clock and direct reset inputs.

FEATURES

- High-speed: (clock frequency) 60MHz typ. ($C_L=15\text{pF}$, $V_{CC}=5\text{V}$)
- Low power dissipation: $20\mu\text{W}/\text{package}$, max ($V_{CC}=5\text{V}$, $T_a=25^\circ\text{C}$, quiescent state)
- High noise margin: 30% of V_{CC} , min ($V_{CC}=4.5\text{V}$, 6V)
- Capable of driving 10 74LS TTL loads
- Wide operating voltage range: $V_{CC}=2\sim 6\text{V}$
- Wide operating temperature range: $T_a=-40\sim +85^\circ\text{C}$

APPLICATION

General purpose, for use in industrial and consumer digital equipment.

FUNCTIONAL DESCRIPTION

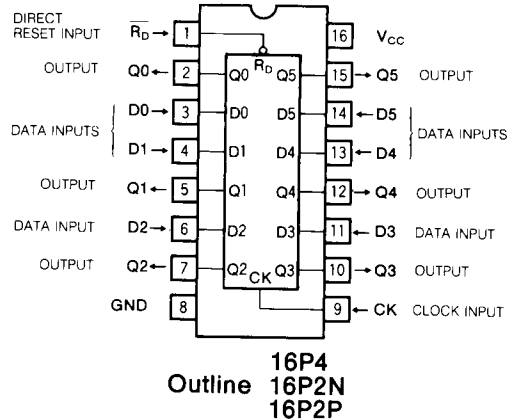
Use of silicon gate technology allows the M74HC174 to maintain the low power dissipation and high noise margin characteristics of the standard CMOS logic 4000B series while giving high-speed performance equivalent to the 74LS174.

The M74HC174 contains six internal edge-triggered D-type flip-flops with common direct reset input R_D and common clock input CK.

When CK changes from low-level to high-level, the signals just previously input D appears at outputs Q in accordance with the function table given. When R_D is low, all outputs Q will become low irrespective of other inputs.

When used as a D-type flip-flop, R_D should be maintained at high-level.

PIN CONFIGURATION (TOP VIEW)

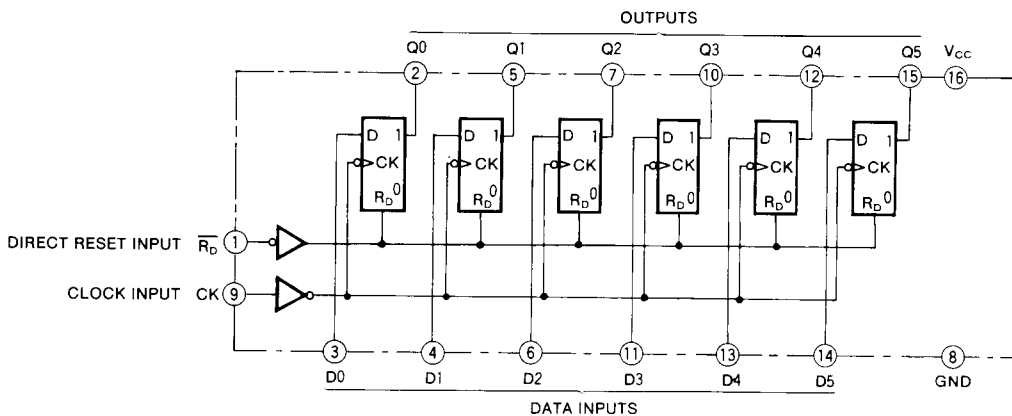


FUNCTION TABLE (Note 1)

Inputs			Outputs
R_D	CK	D	Q
H	↑	H	H
H	↑	L	L
H	↓	X	Q^0
L	X	X	L
H	L	X	Q^0

Note 1 : X : Irrelevant
 ↑ : Change from low to high
 ↓ : Change from high to low
 Q^0 : Output state Q before clock input changed

LOGIC DIAGRAM



HEX D-TYPE FLIP-FLOP WITH COMMON CLOCK AND RESET

ABSOLUTE MAXIMUM RATINGS ($T_a = -40 \sim +85^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Conditions	Ratings	Unit
V_{CC}	Supply voltage		$-0.5 \sim +7.0$	V
V_I	Input voltage		$-0.5 \sim V_{CC} + 0.5$	V
V_O	Output voltage		$-0.5 \sim V_{CC} + 0.5$	V
I_{IK}	Input protection diode current	$V_I < 0V$	-20	mA
		$V_I > V_{CC}$	20	
I_{OK}	Output parasitic diode current	$V_O < 0V$	-20	mA
		$V_O > V_{CC}$	20	
I_O	Output current per output pin		± 25	mA
I_{CC}	Supply/GND current	V_{CC}, GND	± 50	mA
P_d	Power dissipation	(Note 2)	500	mW
T_{stg}	Storage temperature range		$-65 \sim +150$	$^\circ\text{C}$

Note 2 : M74HC174FP, $T_a = -40 \sim +70^\circ\text{C}$ and $T_a = 70 \sim 85^\circ\text{C}$ are derated at $-6\text{mW}/^\circ\text{C}$.
M74HC174DP, $T_a = -40 \sim +50^\circ\text{C}$ and $T_a = 50 \sim 85^\circ\text{C}$ are derated at $-5\text{mW}/^\circ\text{C}$.

RECOMMENDED OPERATING CONDITIONS ($T_a = -40 \sim +85^\circ\text{C}$)

Symbol	Parameter	Limits			Unit
		Min	Typ	Max	
V_{CC}	Supply voltage	2		6	V
V_I	Input voltage	0		V_{CC}	V
V_O	Output voltage	0		V_{CC}	V
T_{opr}	Operating temperature range	-40		+85	$^\circ\text{C}$
t_r, t_f	Input risetime, falltime	$V_{CC} = 2.0V$	0	1000	ns
		$V_{CC} = 4.5V$	0	500	
		$V_{CC} = 6.0V$	0	400	

ELECTRICAL CHARACTERISTICS

Symbol	Parameter	Test conditions	Limits					Unit	
			25 $^\circ\text{C}$			$-40 \sim +85^\circ\text{C}$			
			$V_{CC}(V)$	Min	Typ	Max	Min		Max
V_{IH}	High-level input voltage	$V_O = 0.1V, V_{CC} = 0.1V$ $ I_O = 20\mu\text{A}$	2.0	1.5			1.5	V	
			4.5	3.15			3.15		
			6.0	4.2			4.2		
V_{IL}	Low-level input voltage	$V_O = 0.1V, V_{CC} = 0.1V$ $ I_O = 20\mu\text{A}$	2.0			0.5		0.5	V
			4.5			1.35		1.35	
			6.0			1.8		1.8	
V_{OH}	High-level output voltage	$V_I = V_{IH}, V_{IL}$	$I_{OH} = -20\mu\text{A}$	2.0	1.9			1.9	V
			$I_{OH} = -20\mu\text{A}$	4.5	4.4			4.4	
			$I_{OH} = -20\mu\text{A}$	6.0	5.9			5.9	
			$I_{OH} = -4.0\text{mA}$	4.5	4.18			4.13	
			$I_{OH} = -5.2\text{mA}$	6.0	5.68			5.63	
V_{OL}	Low-level output voltage	$V_I = V_{IH}, V_{IL}$	$I_{OL} = 20\mu\text{A}$	2.0		0.1		0.1	V
			$I_{OL} = 20\mu\text{A}$	4.5		0.1		0.1	
			$I_{OL} = 20\mu\text{A}$	6.0		0.1		0.1	
			$I_{OL} = 4.0\text{mA}$	4.5		0.26		0.33	
			$I_{OL} = 5.2\text{mA}$	6.0		0.26		0.33	
I_{IH}	High-level input current	$V_I = 6V$	6.0			0.1		1.0	μA
I_{IL}	Low-level input current	$V_I = 0V$	6.0			-0.1		-1.0	μA
I_{CC}	Quiescent supply current	$V_I = V_{CC}, \text{GND}, I_O = 0\mu\text{A}$	6.0			4.0		40.0	μA

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SWITCHING CHARACTERISTICS ($V_{CC} = 5V, T_a = 25^\circ C$)

Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
f_{max}	Maximum clock frequency	$C_L = 15pF$ (Note 4)	30			MHz
t_{TLH}	Low-level to high-level and high-level to low-level				10	ns
t_{THL}	output transition time				10	ns
t_{PLH}	Low-level to high-level and high-level to low-level				30	ns
t_{PHL}	output propagation time (CK - Q)				30	ns
t_{PHL}	High-level to low-level output propagation time ($\overline{R_D} - Q$)			30	ns	

SWITCHING CHARACTERISTICS ($V_{CC} = 2\sim 6V, T_a = -40\sim +85^\circ C$)

Symbol	Parameter	Test conditions	Limits					Unit
			25°C			-40~+85°C		
			$V_{CC}(V)$	Min	Typ	Max	Min	
f_{max}	Maximum clock frequency	$C_L = 50pF$ (Note 4)	2.0	5			4	MHz
			4.5	27			21	
			6.0	31			24	
t_{TLH}	Low-level to high-level and high-level to low-level		2.0			75	95	ns
			4.5			15	19	
			6.0			13	16	
t_{THL}	output transition time		2.0			75	95	ns
			4.5			15	19	
			6.0			13	16	
t_{PLH}	Low-level to high-level and high-level to low-level	2.0			165	206	ns	
		4.5			33	41		
		6.0			28	35		
t_{PHL}	output propagation time (CK - Q)	2.0			165	206	ns	
		4.5			33	41		
		6.0			28	35		
t_{PHL}	High-level to low-level output propagation time ($\overline{R_D} - Q$)	2.0			165	206	ns	
		4.5			33	41		
		6.0			28	35		
C_I	Input capacitance				10	10	pF	
C_{PD}	Power dissipation capacitance (Note 3)			64			pF	

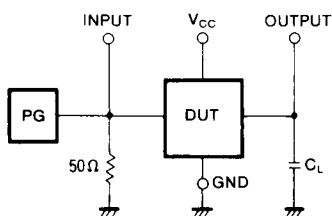
Note 3 : C_{PD} is the internal capacitance of the IC calculated from operation supply current under no-load conditions.
The power dissipated during operation under no-load conditions is calculated using the following formula:
 $P_D = C_{PD} \cdot V_{CC}^2 \cdot f_t + I_{CC} \cdot V_{CC}$

TIMING REQUIREMENTS ($V_{CC} = 2\sim 6V, T_a = -40\sim +85^\circ C$)

Symbol	Parameter	Test conditions	Limits					Unit
			25°C			-40~+85°C		
			$V_{CC}(V)$	Min	Typ	Max	Min	
$t_{W(CK)}$	Clock pulse width		2.0	80			106	ns
			4.5	16			20	
			6.0	14			18	
$t_{W(\overline{R_D})}$	Direct reset pulse width		2.0	80			106	ns
			4.5	16			20	
			6.0	14			18	
t_{su}	D setup time with respect to CK		2.0	100			125	ns
			4.5	20			25	
			6.0	17			21	
t_h	D hold time with respect to CK	2.0	5			5	ns	
		4.5	5			5		
		6.0	5			5		
t_{rec}	$\overline{R_D}$ recovery time with respect to CK	2.0	5			5	ns	
		4.5	5			5		
		6.0	5			5		

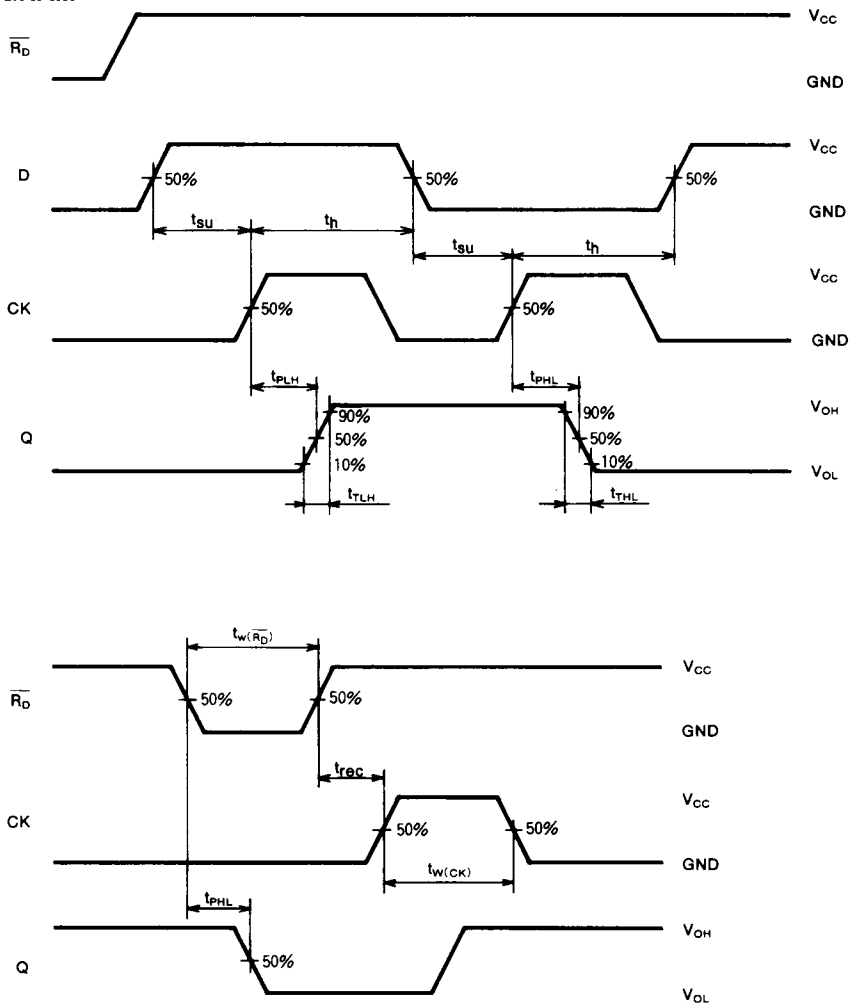
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Note 4 : Test Circuit



- (1) The pulse generator (PG) has the following characteristics (10%~90%): $t_r = 6\text{ns}$, $t_f = 6\text{ns}$
- (2) The capacitance C_L includes stray wiring capacitance and the probe input capacitance.

TIMING DIAGRAM



MITSUBISHI HIGH SPEED CMOS
PACKAGE OUTLINES

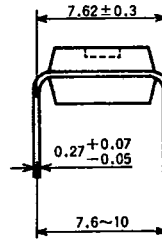
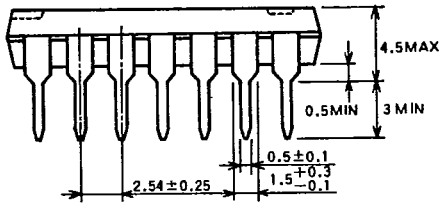
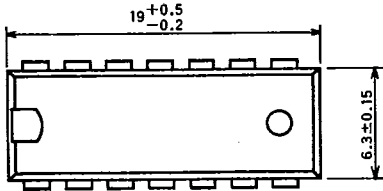
6249827 MITSUBISHI (DGTL LOGIC)

91D 12849

D T-90-20

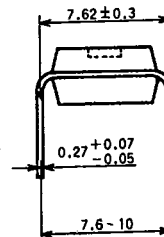
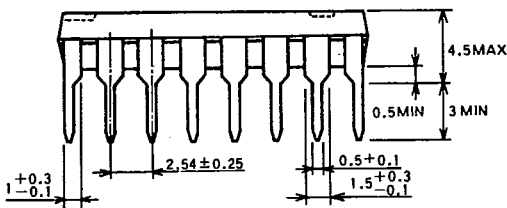
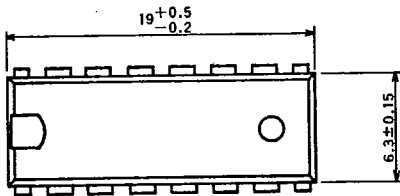
TYPE 14P4 14-PIN MOLDED PLASTIC DIP

Dimension in mm



TYPE 16P4 16-PIN MOLDED PLASTIC DIP

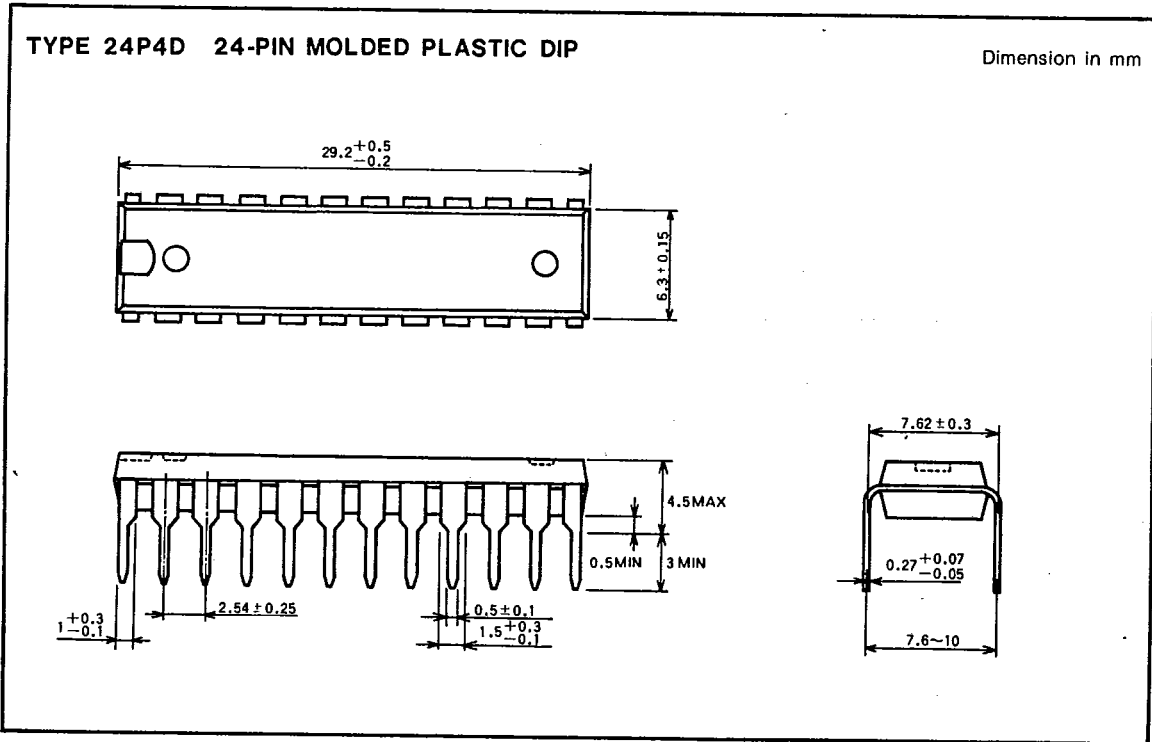
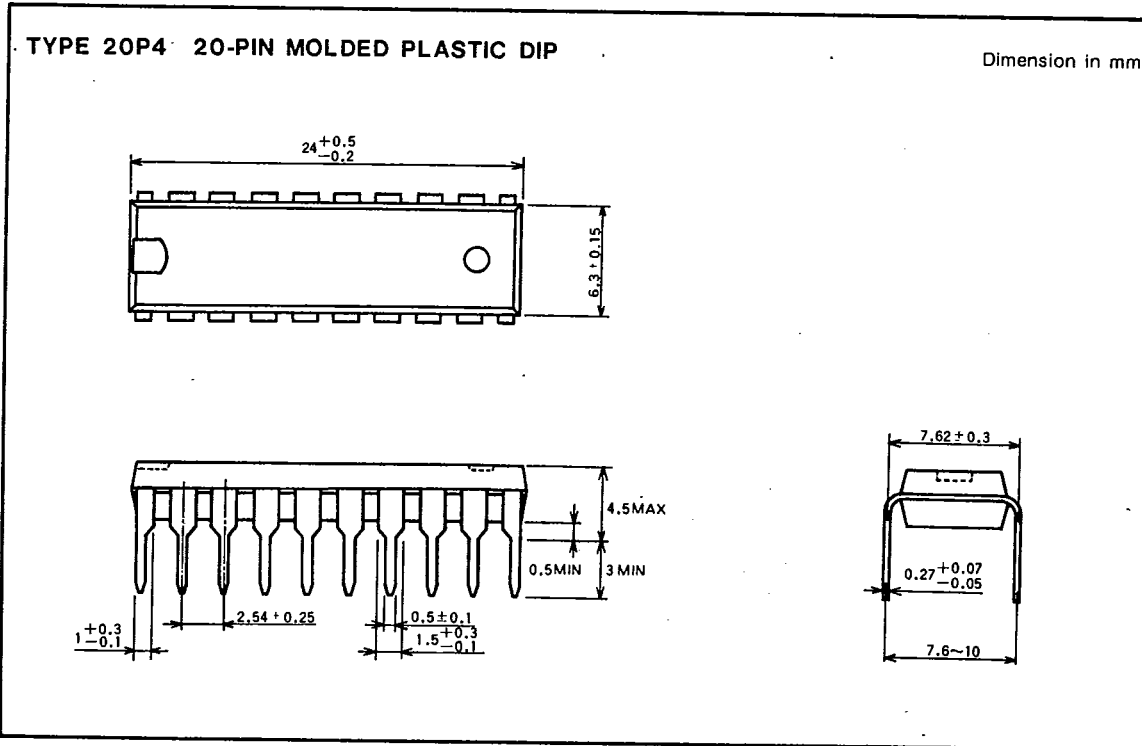
Dimension in mm



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91D 12850 D.T-90-20



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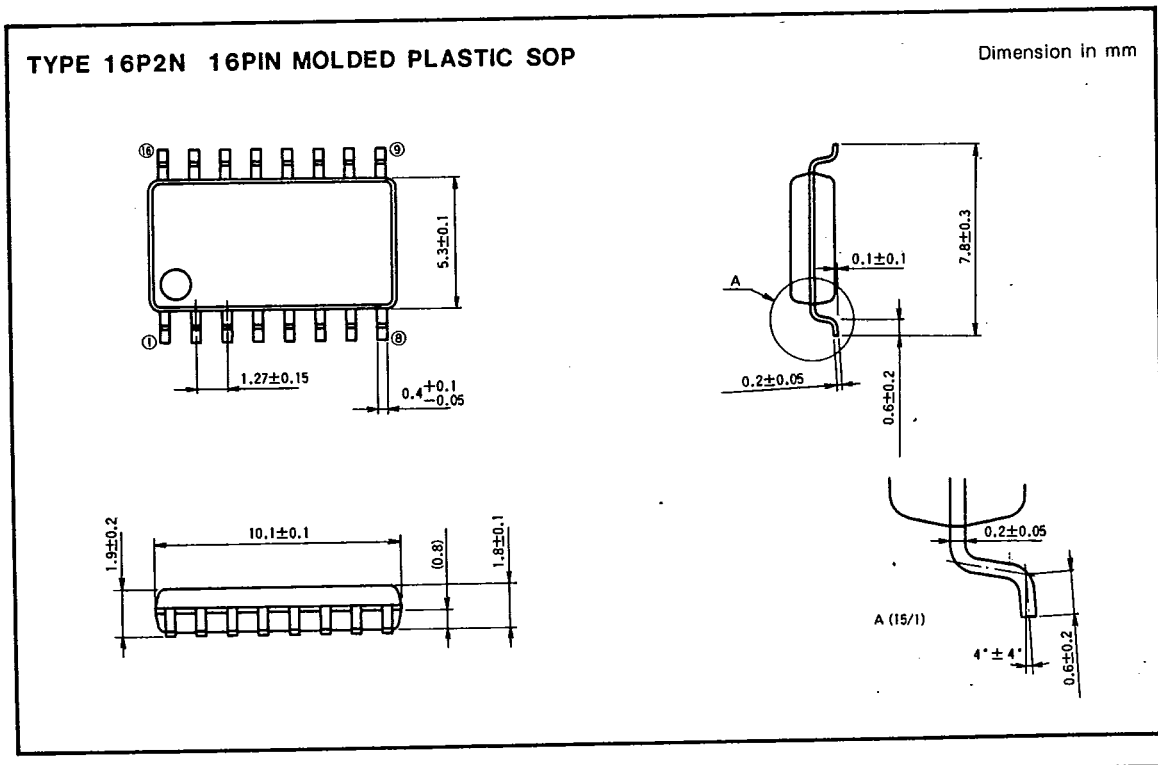
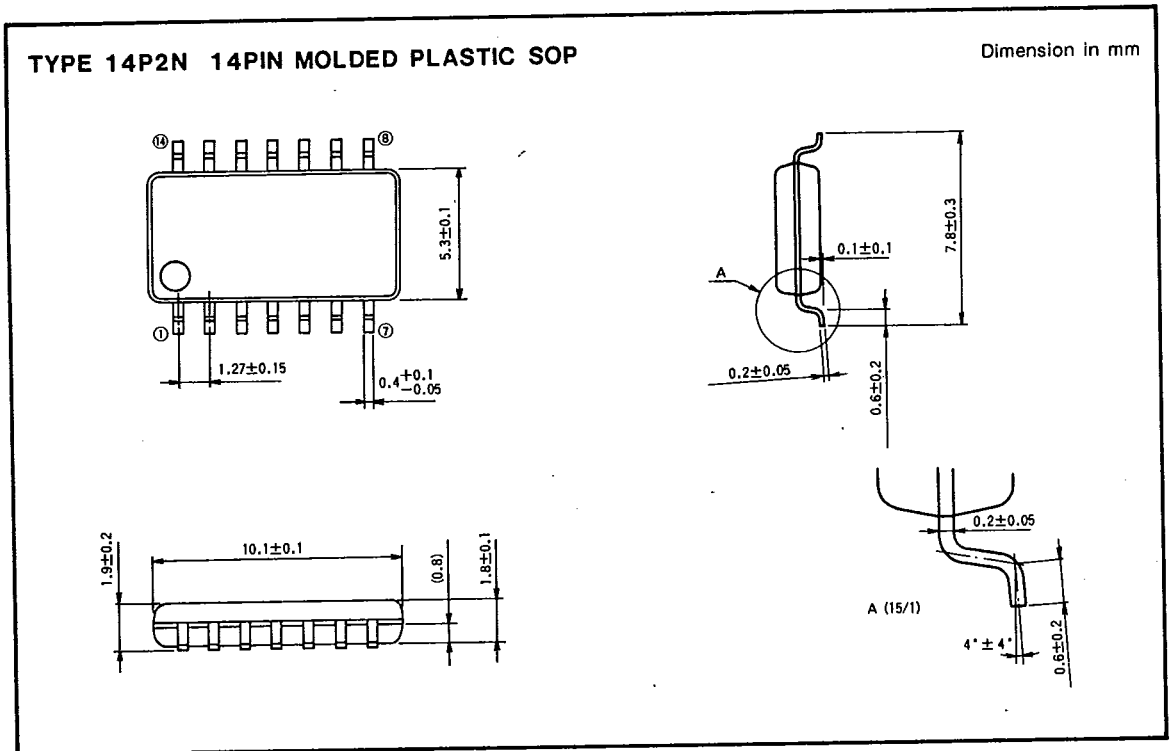


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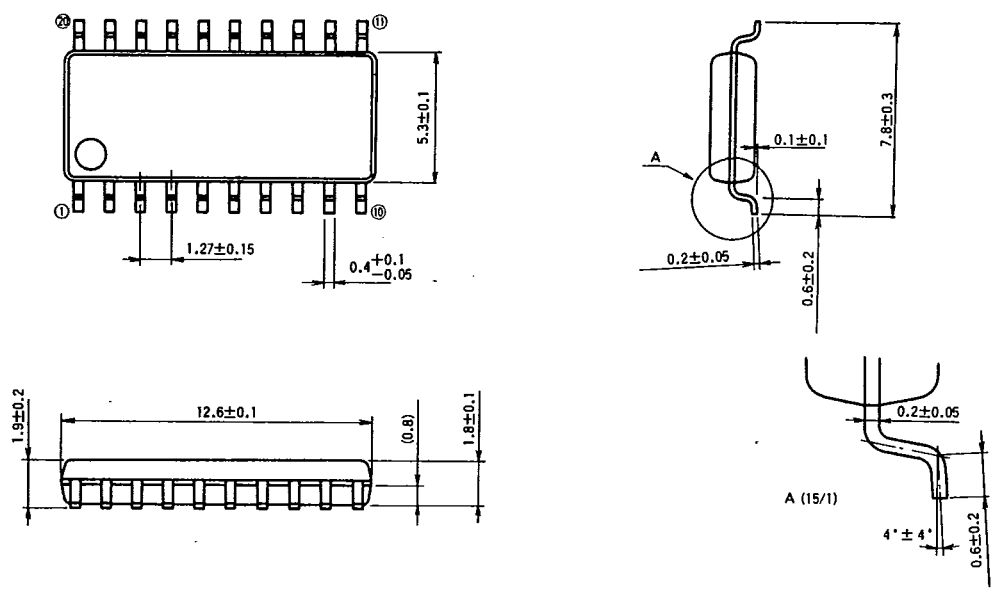
6249827 MITSUBISHI (DGTL LOGIC)

91D 12851 D T-90.20



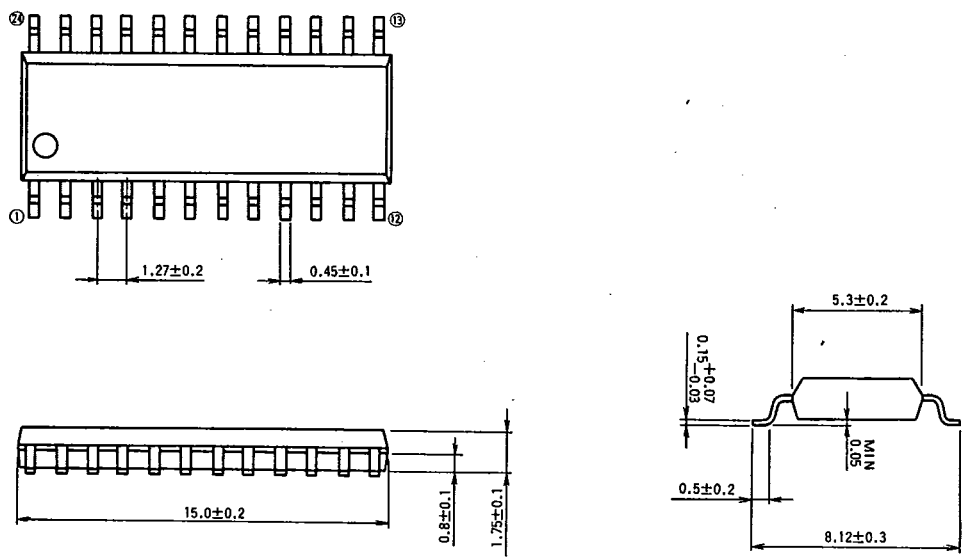
TYPE 20P2N 20PIN MOLDED PLASTIC SOP

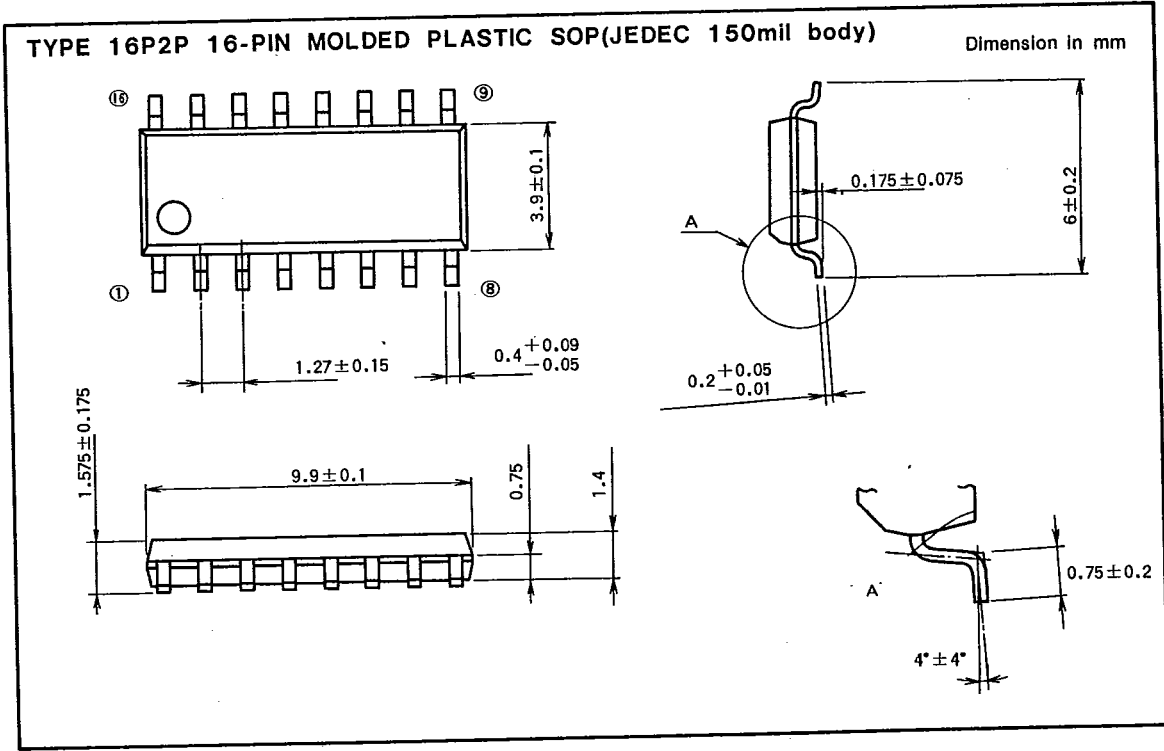
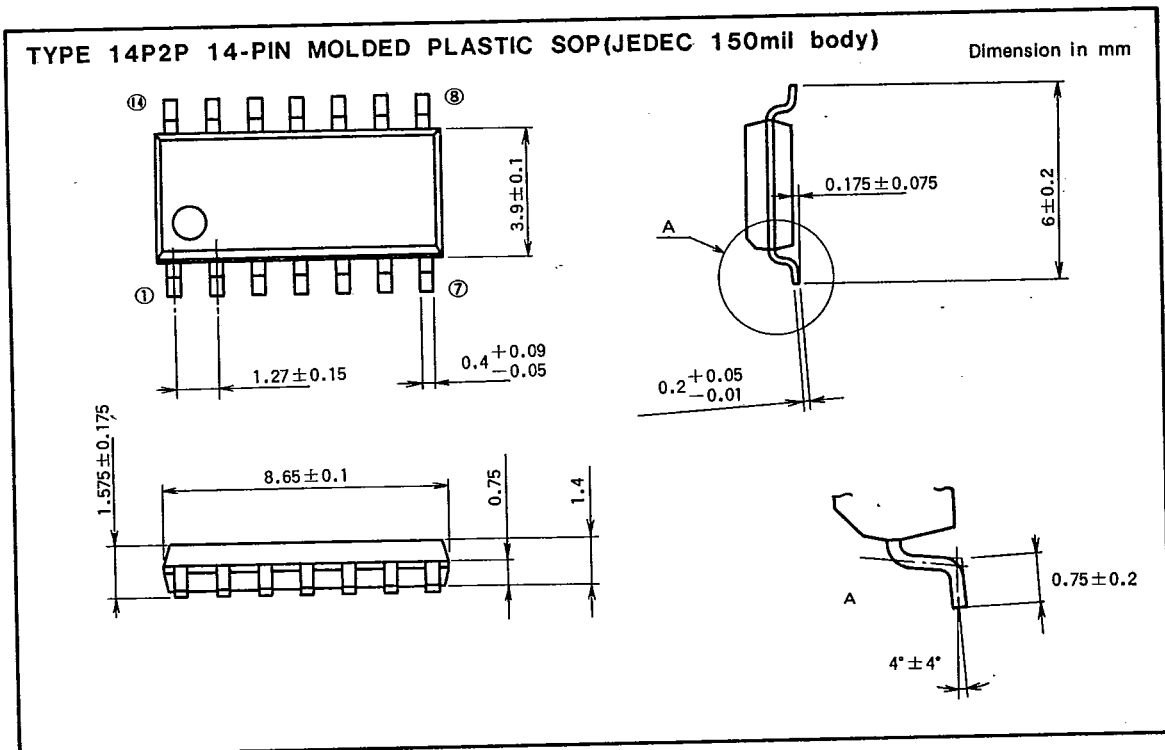
Dimension in mm



TYPE 24P2 24PIN MOLDED PLASTIC SOP

Dimension in mm





MITSUBISHI HIGH SPEED CMOS
PACKAGE OUTLINES

6249827 MITSUBISHI (DGTL LOGIC)

91D 12854 D T-90-20

